

INTERNATIONAL STANDARD

IEC 60410

First edition
1973

Sampling plans and procedures for inspection by attributes

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Withdrawn

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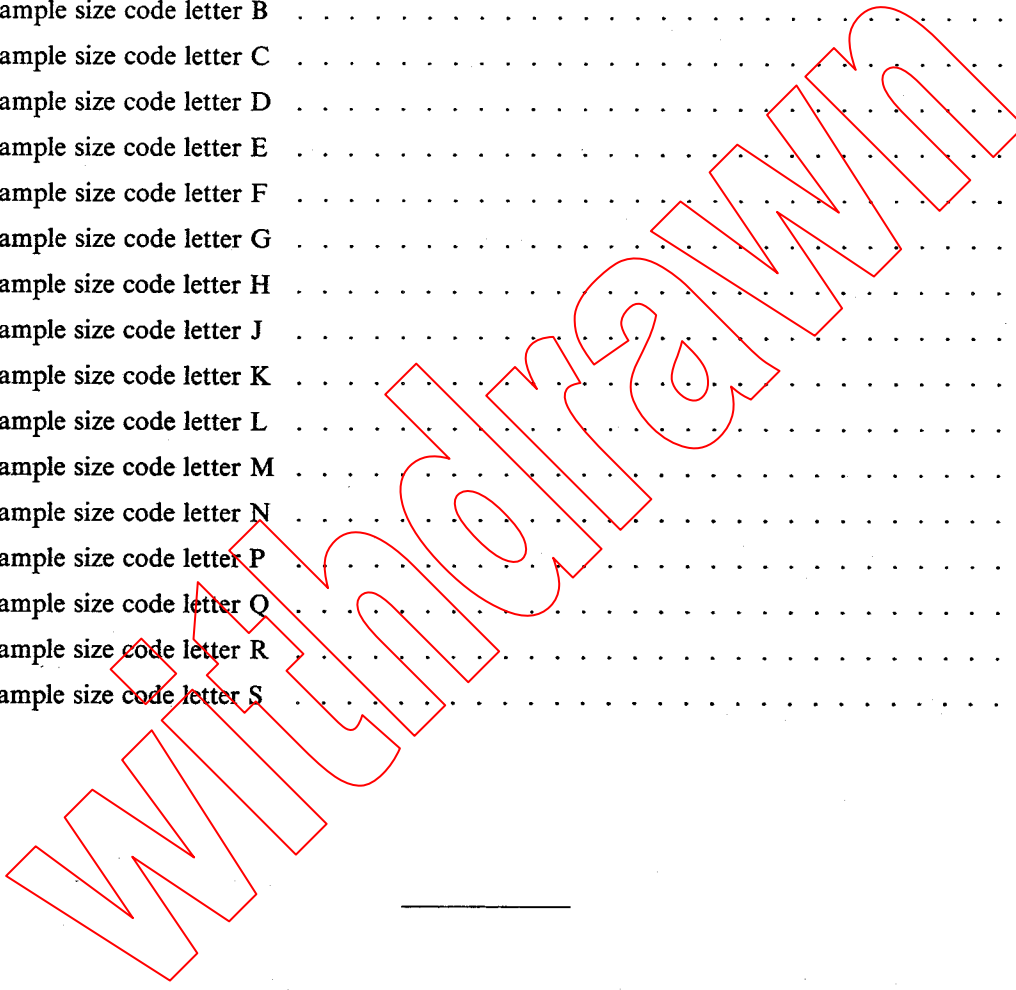
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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**SAMPLING PLANS AND PROCEDURES
FOR INSPECTION BY ATTRIBUTES**

FOREWORD

- 1) The formal decisions or agreements of the IEC on technical matters, prepared by Technical Committees on which all the National Committees having a special interest therein are represented, express, as nearly as possible, an international consensus of opinion on the subjects dealt with.
- 2) They have the form of recommendations for international use and they are accepted by the National Committees in that sense.
- 3) In order to promote international unification, the IEC expresses the wish that all National Committees should adopt the text of the IEC recommendation for their national rules in so far as national conditions will permit. Any divergence between the IEC recommendations and the corresponding national rules should, as far as possible, be clearly indicated in the latter.

PREFACE

This recommendation has been prepared by IEC Technical Committee No. 56, Reliability of Electronic Components and Equipment.

A draft was discussed at the meeting held in Washington in May 1970. As a result, a draft, document 56(Central Office)29, was circulated to the National Committees for approval under the Six Months' Rule in September 1970.

The following countries voted explicitly in favour of publication:

Australia	Netherlands
Belgium	South Africa
Canada	Spain
Czechoslovakia	Sweden
Denmark	Switzerland
Finland	Turkey
France	Union of Soviet
Germany	Socialist Republics
Israel	United Kingdom
Italy	United States of America

SAMPLING PLANS AND PROCEDURES FOR INSPECTION BY ATTRIBUTES

1. Scope

1.1 Purpose

This recommendation establishes sampling plans and procedures for inspection by attributes. When specified by the responsible authority, this recommendation shall be called up in the specification, contract, inspection instructions or other documents and the provisions set forth herein shall govern. The “responsible authority” shall be designated in one of the above documents.

Note. — The responsible authority may be the customer.

1.2 Application

Sampling plans designated in this publication are applicable, but not limited, to inspection of the following:

- a) end items
- b) components and raw materials
- c) operations
- d) materials in process
- e) supplies in storage
- f) maintenance operations
- g) data or records
- h) administrative procedures.

These plans are intended primarily to be used for a continuing series of lots or batches. The plans may also be used for the inspection of isolated lots or batches, but in this latter case, the user is cautioned to consult the operating characteristic curves to find a plan which will yield the desired protection (see Sub-clause 11.6).

1.3 Inspection

Inspection is the process of measuring, examining, testing or otherwise comparing the unit of product (see Sub-clause 1.5) with the requirements.

1.4 Inspection by attributes

Inspection by attributes is inspection whereby either the unit of product is classified simply as defective or non-defective or the number of defects in the unit of product is counted, with respect to a given requirement or set of requirements.

1.5 Unit of product

The unit of product is the thing inspected in order to determine its classification as defective or non-defective or to count the number of defects. It may be a single article, a pair, a set, a length, an area, an operation, a volume, a component of an end product, or the end product itself. The unit of product may or may not be the same as the unit of purchase, supply, production or shipment.